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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
IM	AA	4,792,958	12/20/88	OHBA, et al.	372	4501	\	
''' / -	AB	4,809,287	02/28/89	OHBA, et al.	300	45.01	\	
 	AC	4,835,117	05/30/89	OHBA, et al.	439	4/1		
	AD ·	4,949,349	08/14/90	OHBA, et al.	372	4501	\	
 	AE	4,910,743	03/20/90	OHBA, et al.	372	45.0		
 	AF	4,928,285	05/22/90	KUSHIBE, et al.	37a	12:01		
}	AG	4,893,313	01/09/90	HATAKOSHI, et al.	200	73.01		
	├		12/31/91	MILNES, et al.	439	394	· 	
	AH	5,076,800	 			4001		
	Al	<5,036,521	07/30/91	HATAKOSHI, et al.	372	75,01		
	AJ	5,168,077	12/01/92	ASHIZAWA, et al.	702	102		
 	AK	5,042,043	08/20/91	HATANO, et al.	2,59	45,012		
	AL	5,005,057	04/02/91	IZUMIYA, et al.	257	13		
11112	AM	5,079,184	01/07/92	HATANO, et al.	11/1	102		
	AN	5,103,271	04/07/92	IZUMIYA, et al.	257	179	· \	
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	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pp. L 905 - L 906, "FABRICATION AND AW GHARACTERIZATION OF AIGHNIGHN BOUBLE LIFTEROLASER STRUCTURES ON SAPPHIRE SUBSTRATES USING							
	SINGLE CRYSTALLINE AIN BUFFER LAYERS," August 1, 1998.							
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TWO	AA	5,228,044	07/13/93	ОНВА	372	45,0		
	AB	5,235,194	08/10/93	IZUMIYA, et al.	85 1	13.11		
	AC	5,273,933	12/28/93	HATANO, et al.	170	29	\	
	AD	. 5,317,167	05/31/94	IZUMIYA, et al.	257	93		
	AE	5,432,808	07/11/95	HATANO, et al.	342	450		
	AF	5,617,438	04/01/97	HATANO, et al.	1372	45.01		
	AG	5,740,192	04/14/98	HATANO, et al.	308	45,01		
	AH	5,998,810	12/07/99	HATANO, et al.	257	102	\.	
	Al	6,242,764	06/05/01	Y. OHBA, et al.	250	190		
	AJ	5,990,495	11/23/99	Y. OHBA	RCD.	94		
	AK	5,656,832	06/01/99	Y. OHBA, et al.	550	190		
	AL	5,909,040	06/01/99	Y. OHBA, et al.	\$ 50	19/1)		
1 10	AM	5,929,466	07/27/99	Y. OHBA, et al.	257	103		
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11/		AA	5,146,465	09/92	KHAN, et al.	372	45.01		
- <u>'-'</u>		AB	6,259,122	07/01	OTA, et al.	257	10).		
		AC	:5,875,052	02/99	SHMAGIN, et al.	359	244	\	
		AD	6,306,672 B1	10/01	KIM	1438	2.0	\	
		AE	6,046,464	04/00	SCHETZINA	257	96	· .	
		AF	6,440,823 B1	08/02	VAUDO, et al.	438	478	_ \ .	
T,		AG	5,929,467	07/99	KAWAI, et al.	257	192		
im	5	AH	5,923,058	07/99	AGARWAL, et al.	1257	199		
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